

WEST Search History

DATE: Tuesday, March 01, 2005

| <u>Hide?</u> | <u>Set Name</u> | <u>Query</u> | <u>Hit Count</u> |
|--|-----------------|--------------------------------|------------------|
| <i>DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=ADJ</i> | | | |
| <input type="checkbox"/> | L20 | L19 and test pattern generat\$ | 39 |
| <input type="checkbox"/> | L19 | L18 and 324/\$.ccls. | 320 |
| <input type="checkbox"/> | L18 | L17 and (BIST or self test), | 5344 |
| <input type="checkbox"/> | L17 | L1 and memory | 220180 |
| <input type="checkbox"/> | L16 | l4 and 324/\$.ccls. | 114 |
| <input type="checkbox"/> | L6 | L5 and inverter | 147 |
| <input type="checkbox"/> | L5 | L4 and test data | 430 |
| <input type="checkbox"/> | L4 | L3 and memory | 890 |
| <input type="checkbox"/> | L3 | L2 AND clock | 1170 |
| <input type="checkbox"/> | L2 | L1 and test pattern generat\$ | 1933 |
| <input type="checkbox"/> | L1 | (IC or integrated circuit) | 1469205 |

END OF SEARCH HISTORY

For 10/647506